

6<sup>th</sup> Korea-Japan PHENIX/sPHENIX/RHICf/EIC Collaboration Meeting

# **INTT Bus Extender Performance**

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**Nara Women's Univ.**

**on behalf of the sPHENIX-INTT group**

**July 16<sup>th</sup>, 2021**

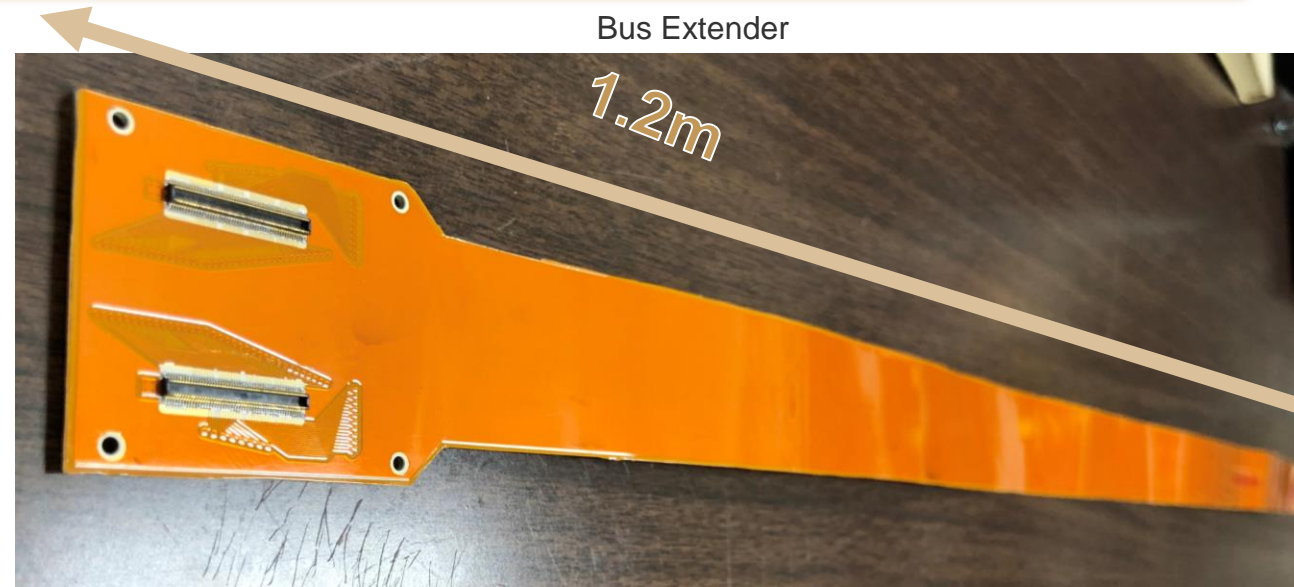
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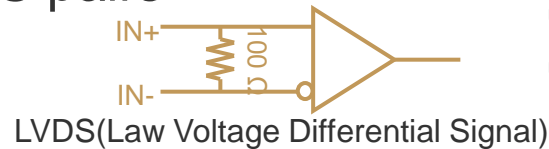


# Bus Extender

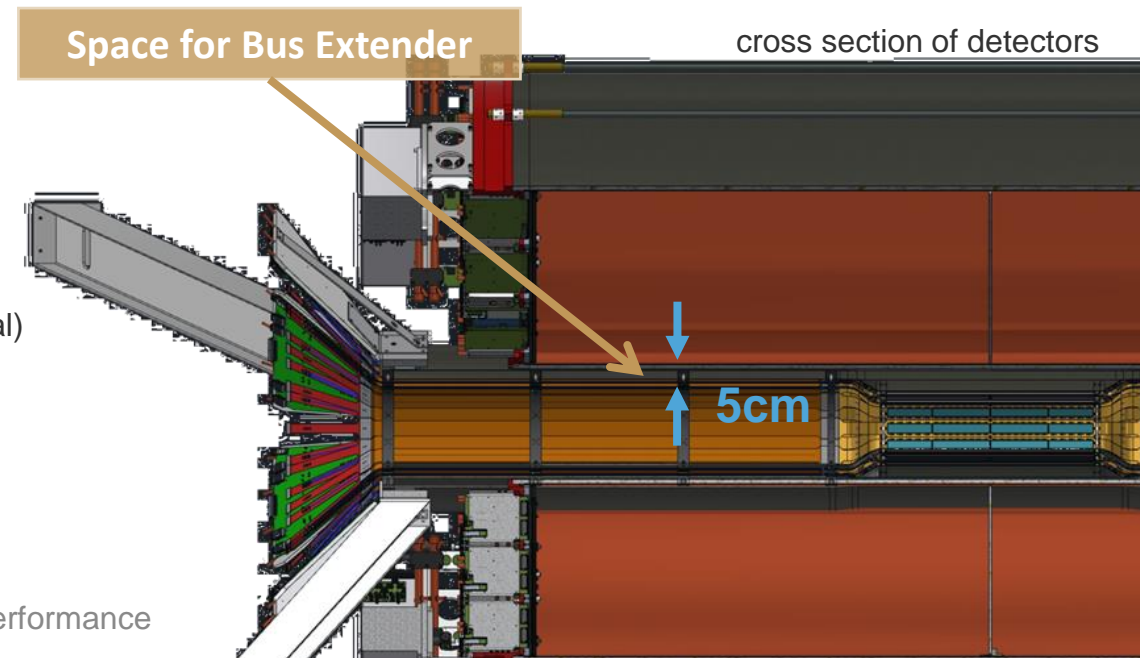
- Requirements of advanced technique
    - Data Transfer : 12 Gbps
    - Length : more 1.2 m
    - Flexibility : freely handled in a narrow space
- There is no commercial cable available.



- To develop a high-signal-density cable using flexible printed cable technology
  - density : 130  $\mu\text{m}$   $\times$  62 LVDS pairs
  - speed : 200 Mbps / pair



- **Introduce New Technology**
  - **Using a liquid crystal polymer(LCP) as substrate**



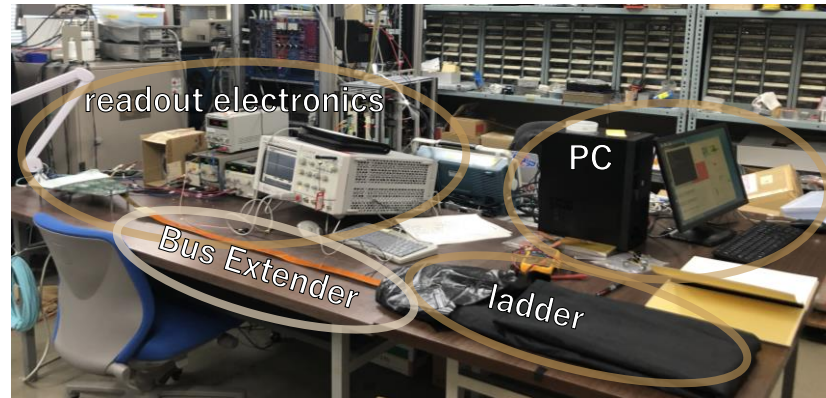


# Measurements

## Electrical Property

To see the performance of the signal transmission with the actual INTT setup,

- Compare the test pulse results w/ and w/o the Bus Extender
  1. Data quality itself
  2. Pulse shape of the signal transmission



Testbench @NWU

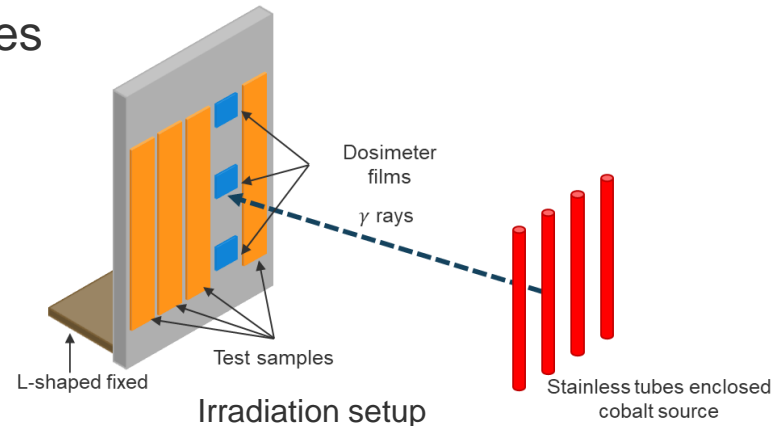


Measurement of output signal using oscilloscope

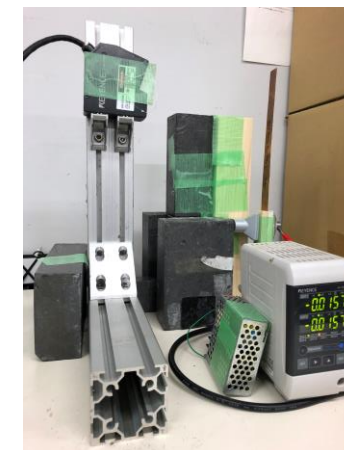
## Mechanical Property

To assess the long-term stability and radiation hardness

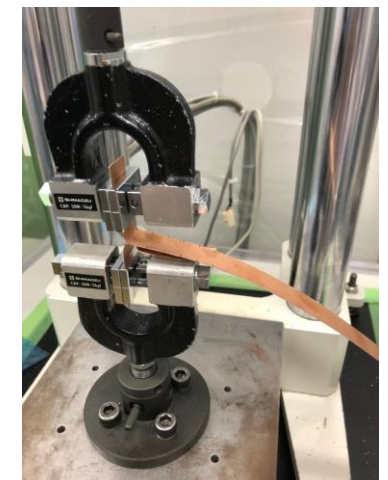
- Irradiation test using several test samples
  1. Young's modulus
  2. Peeling strength



INTT Bus Extender Performance



Measurement of natural frequency



Peeling test by universal tester

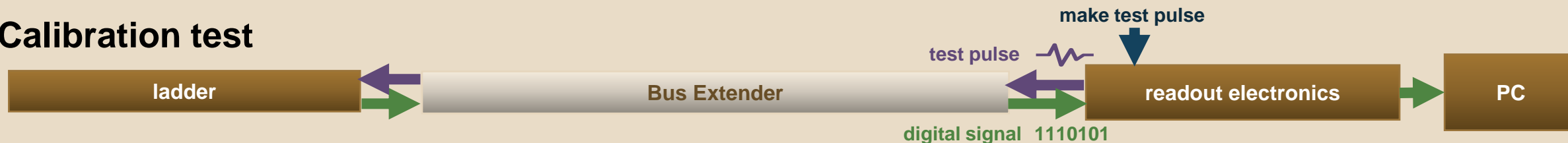


# Data acquisition

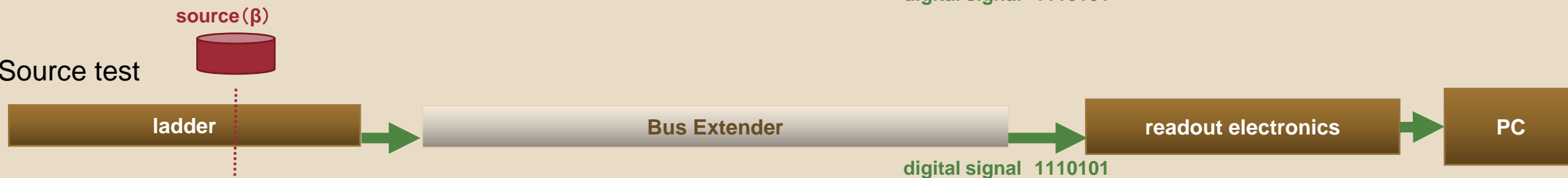
- In Nara Women's University, we have built a test bench and evaluated performance of INTT ladders
  - Three kinds of measurements (using **test pulse**, source, or cosmic)

## Testbench for INTT

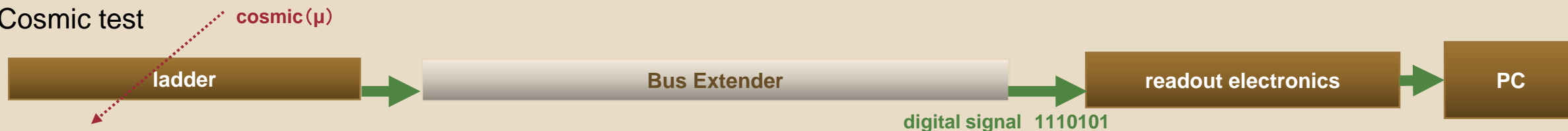
### Calibration test



### Source test



### Cosmic test







# Data acquisition using test pulse

## Purpose

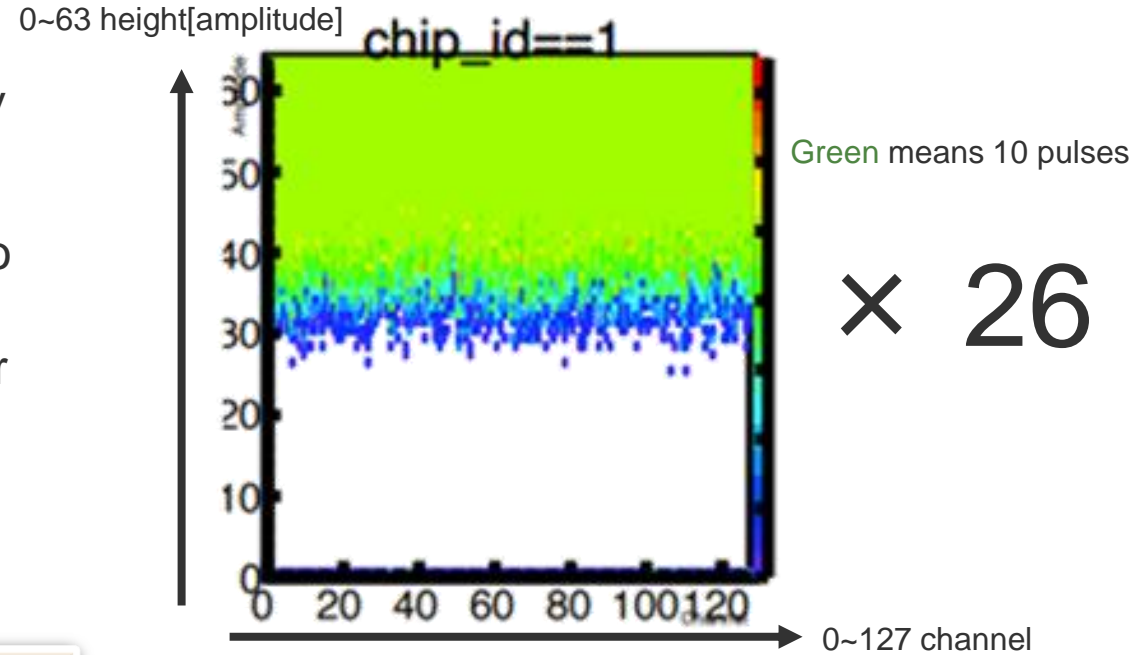
Evaluate whether signals are sent and received normally

## How to

- Test pulse with 64 different heights are sent to each channel (3328 channels) 10 times
- Set a threshold, convert from 64 to 8 levels of pulse height

## Procedure

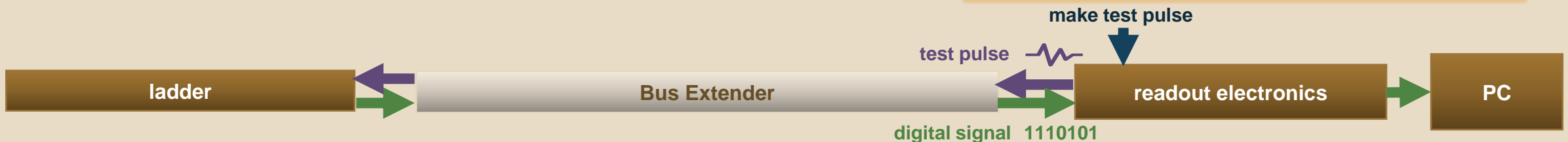
1. Generate test pulse by readout electronics
2. Convert from analog to digital signals by readout chips in ladder
3. Send digital signal from ladder to PC



## Testbench for INTT



Compare measurement  
‘w/ Bus Extender’ with  
‘w/o Bus Extender’



# Data Analysis

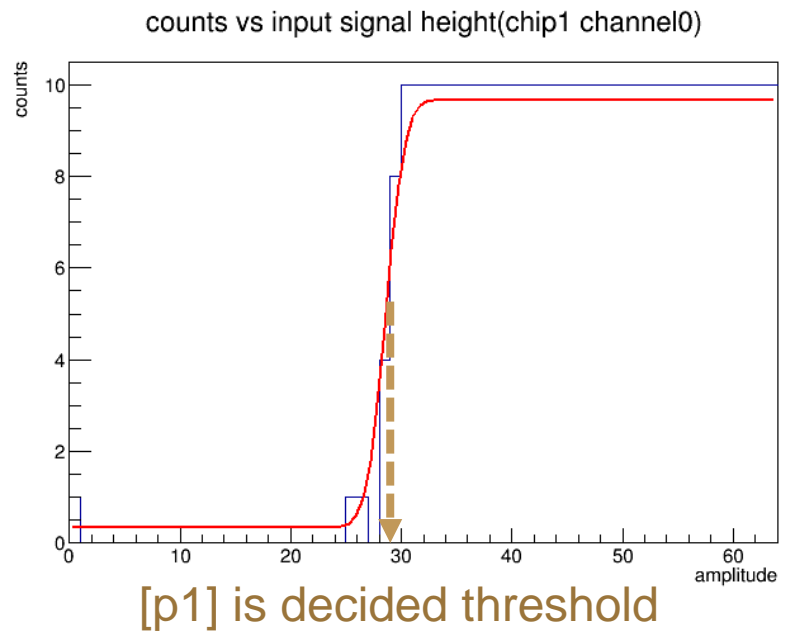
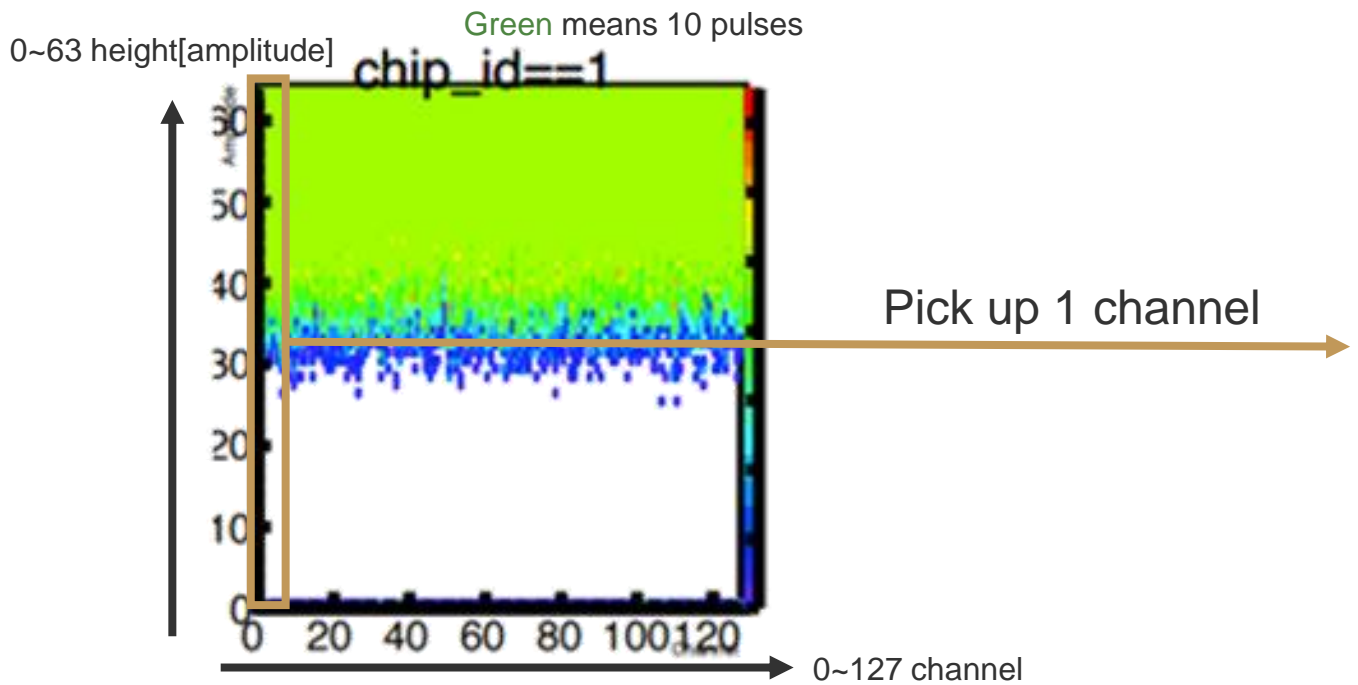
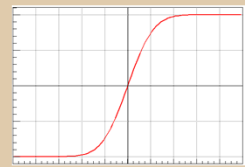
- Evaluate the threshold using the test pulse data
- Compare the threshold value w/ and w/o Bus Extender

**Calculate parameter from Fit function**

Fit func :  $f(x) = [p0] \times \text{erf}((x - [p1]) / [p2]) + 5$

※[p0], [p1] and [p2] are parameters

Error func : erf(x)

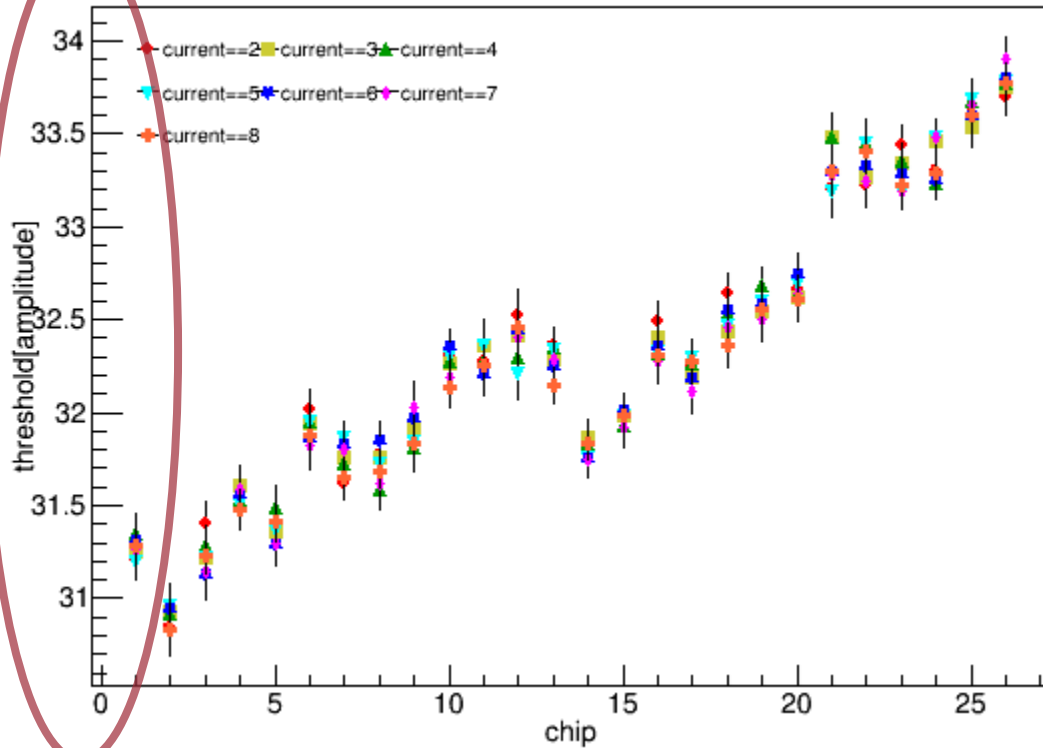
$$\text{erf}(x) = \frac{2}{\sqrt{\pi}} \int_0^x e^{-t^2} dt$$




# Threshold of input signal

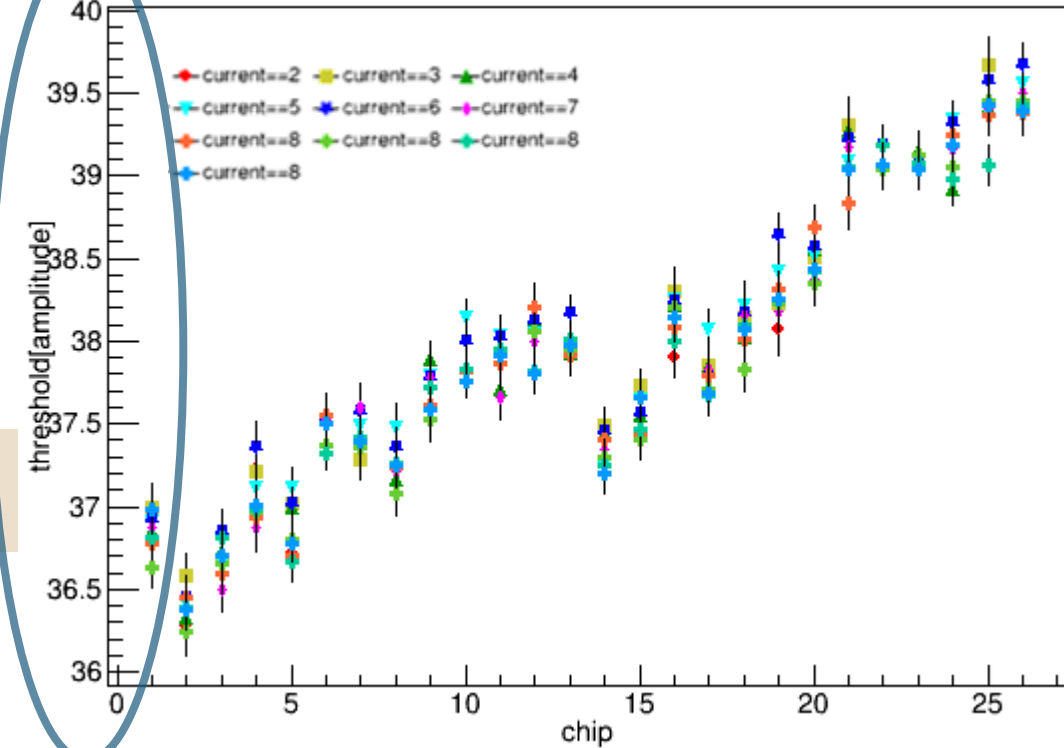
**30.5 ~ 34.0 [amplitude]**

threshold[amplitude] vs chip without Bus-extender



**36.0 ~ 40.0 [amplitude]**

threshold[amplitude] vs chip with Bus-extender



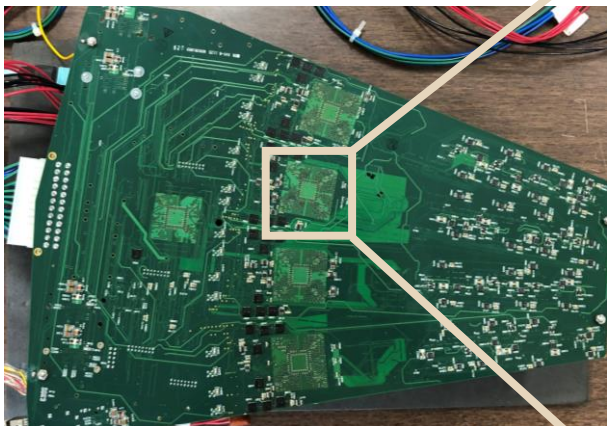
Using Bus Extender

**The result shows the higher threshold w/ Bus Extender. This indicates the test pulse is attenuated by the Bus Extender. I confirm the acquisition rate of test pulses over the threshold.**

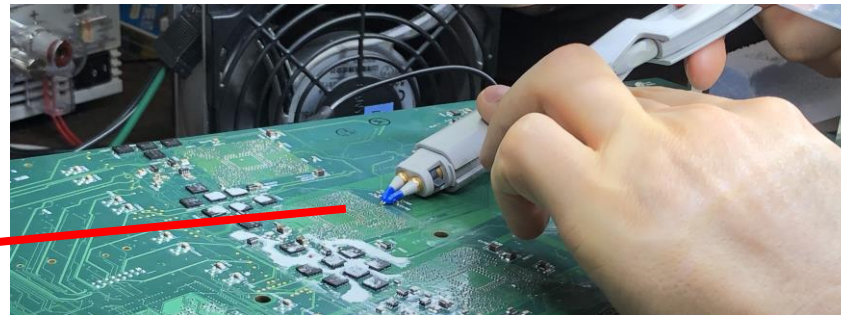




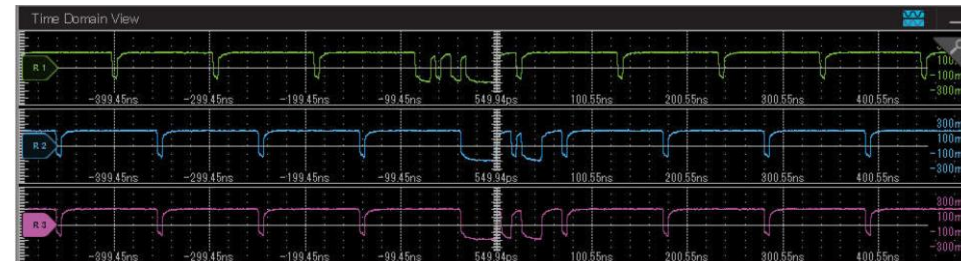
# observe digital output signal by oscilloscope



Back of one of readout electronics

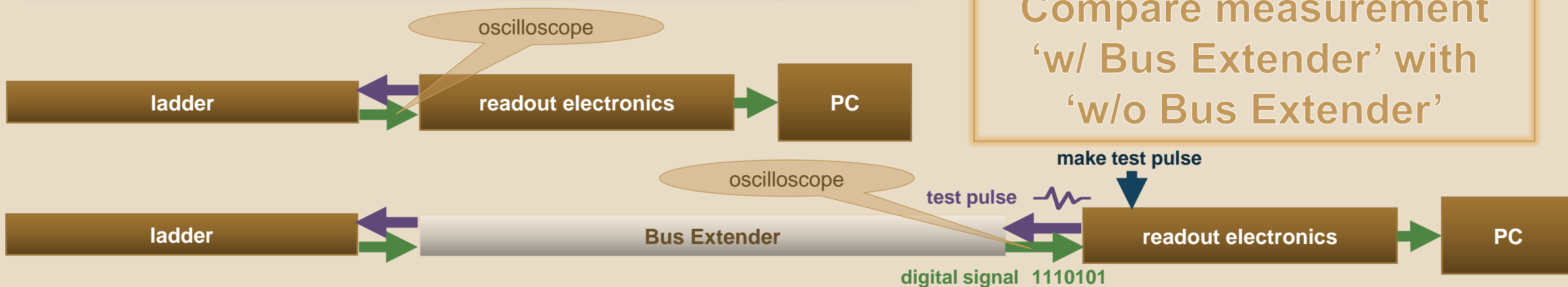


To observe output digital signal with differential probe



Output waveform measured with oscilloscope

## Testbench for INTT

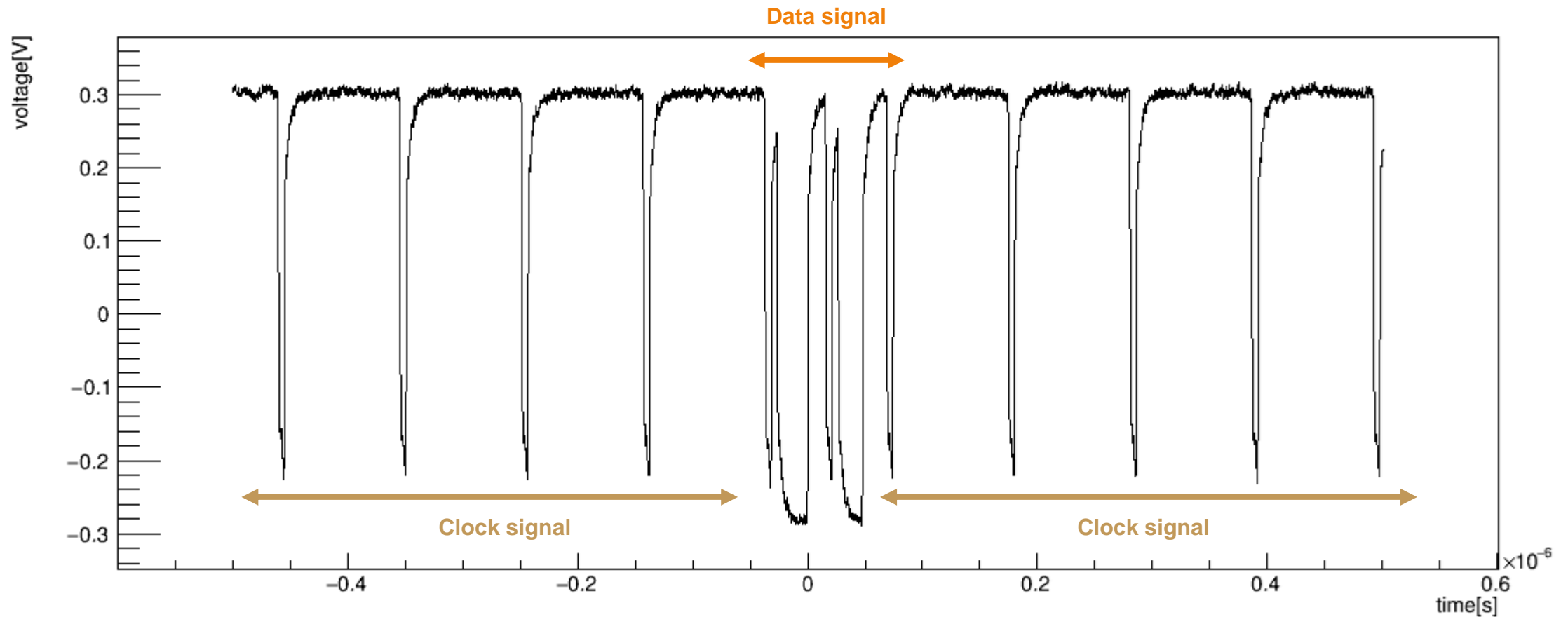


Compare measurement 'w/ Bus Extender' with 'w/o Bus Extender'

# Output signal waveform

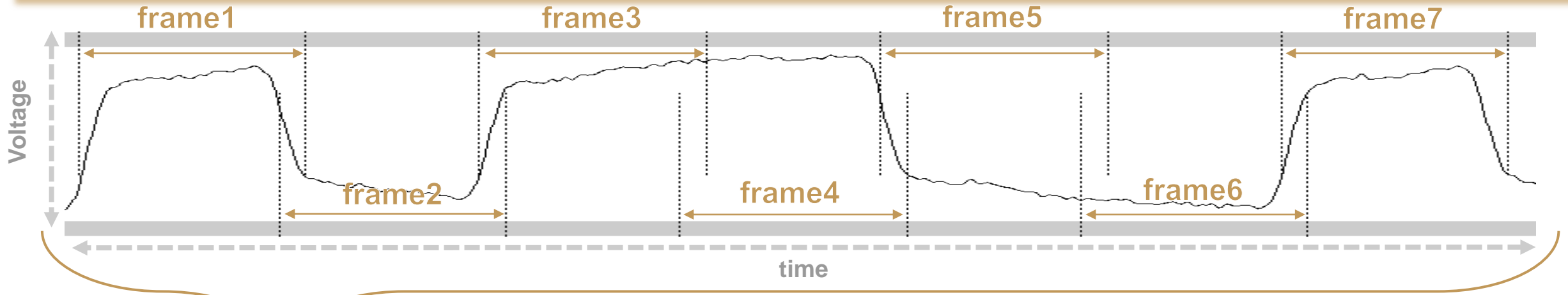
## Observe digital output signal using the oscilloscope

- This graph is output signal waveform w/o Bus Extender
- make eyediagram from this graph and analyze

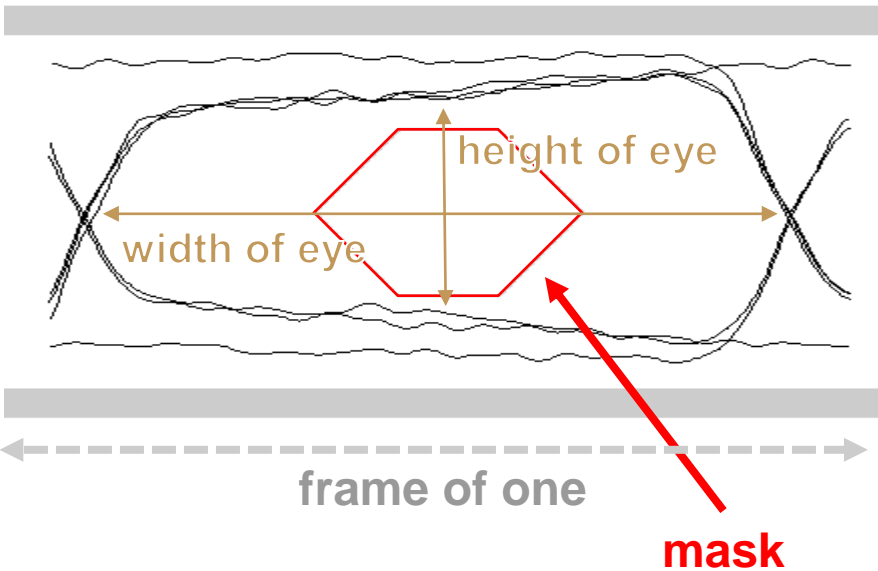




# Eyediagram



Eyediagram

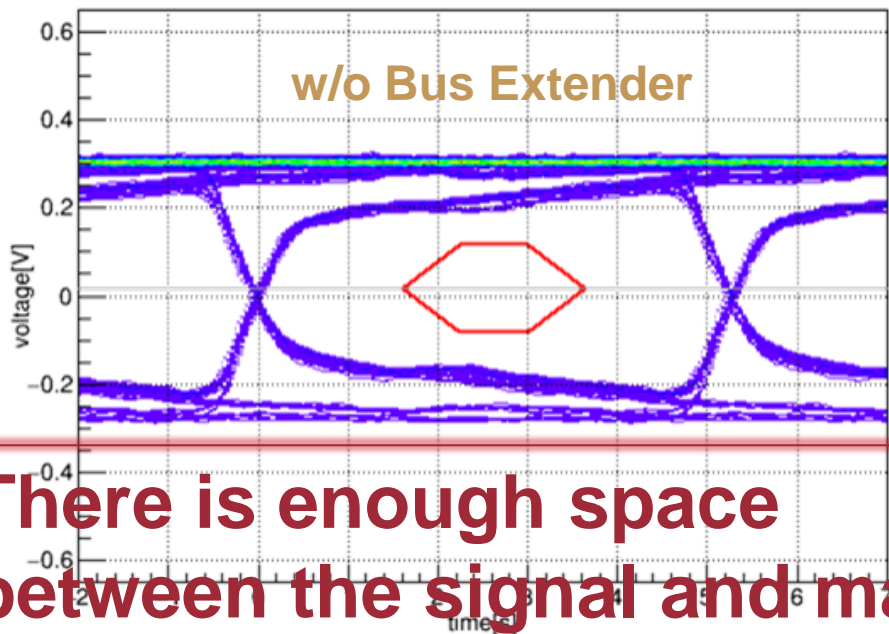


## Eyediagram

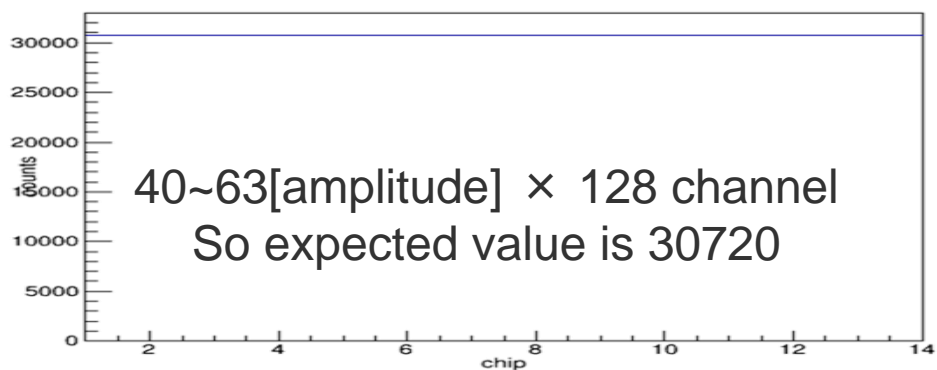
- **To visualize distortion of a waveform when a signal is sent**
- The eye diagram is made by slicing the data into single pulses and overlaying them
  - It looks like an eye —> 「Eye」 diagram
- We can evaluate voltage and margin of timing from eye height and width
- Mask indicates minimum height and width to need to judge correct data
  - We confirm whether signal observed touch mask
  - Mask is defined that error rate is lower than  $10^{-12}$



# Compare eyediagram with received entries



**There is enough space between the signal and mask**



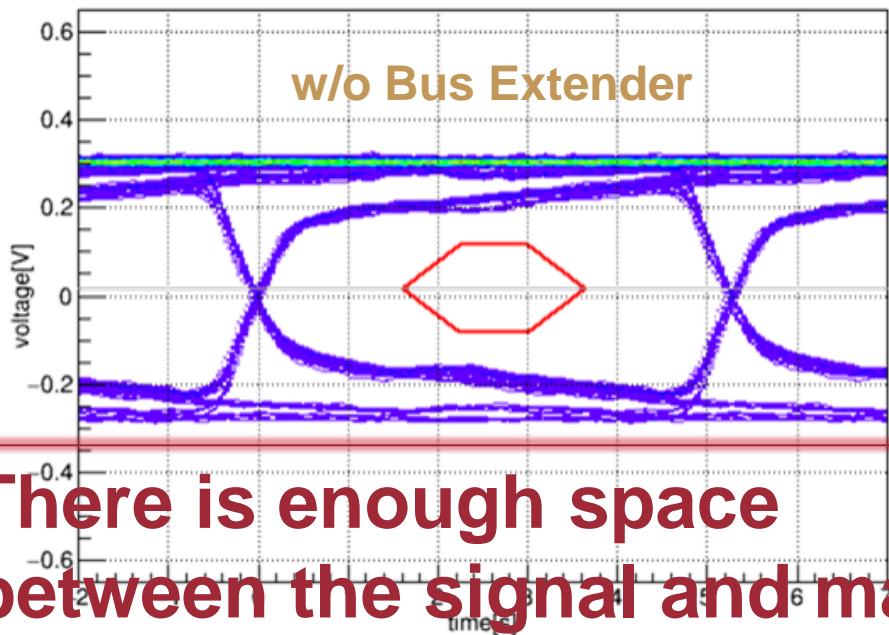
Using Bus Extender

**100% Successfully received**

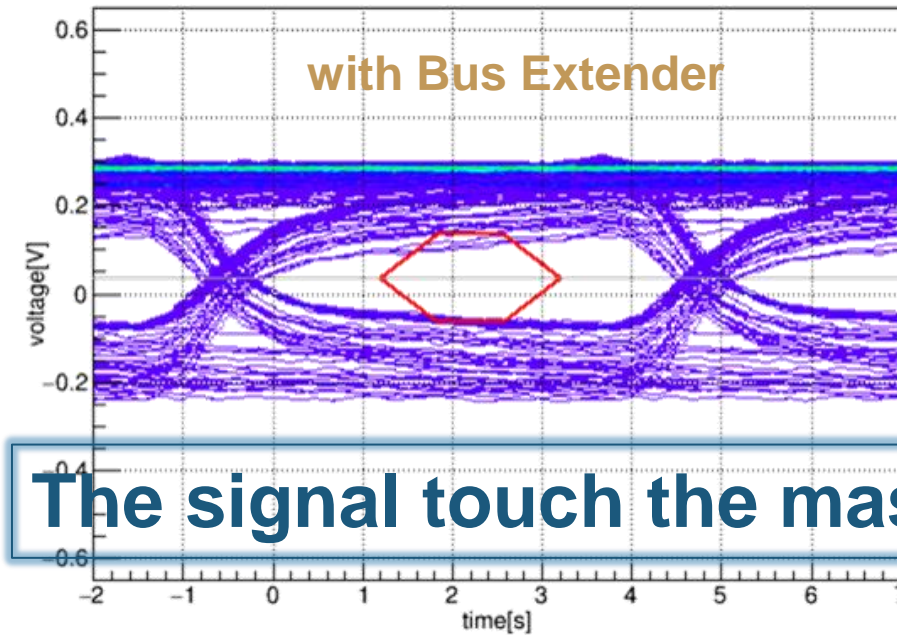


# Compare eyediagram with received entries

3mA

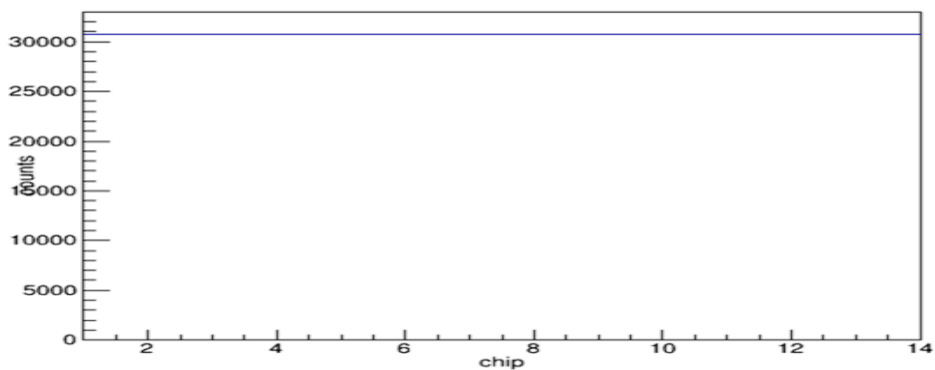


There is enough space between the signal and mask

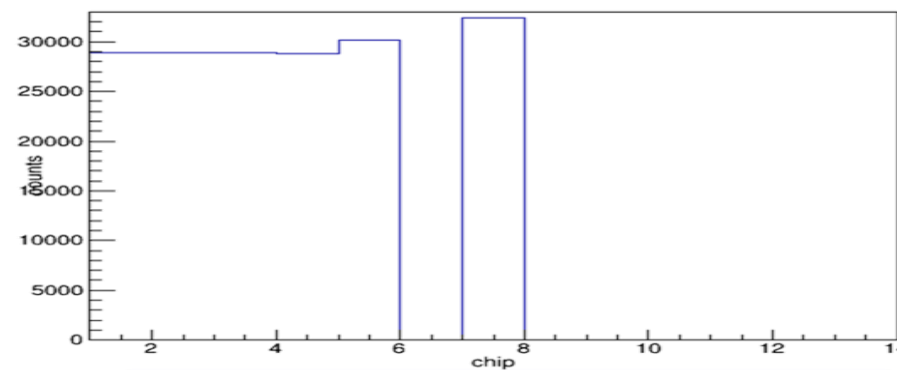


The signal touch the mask

Using Bus Extender



100% Successfully received



Transmission failed





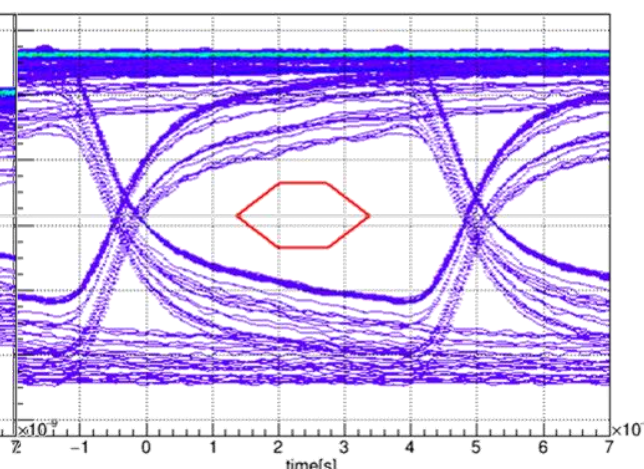
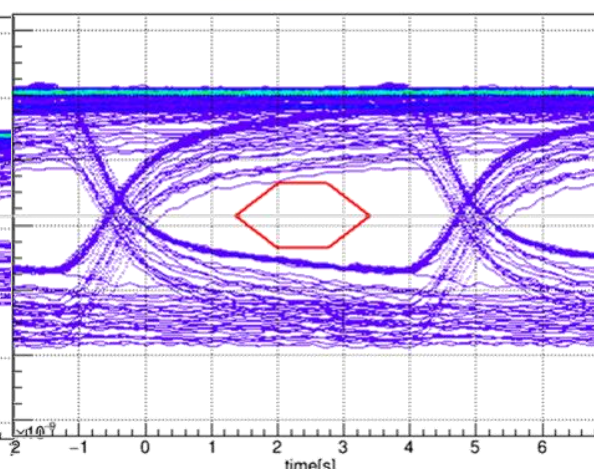
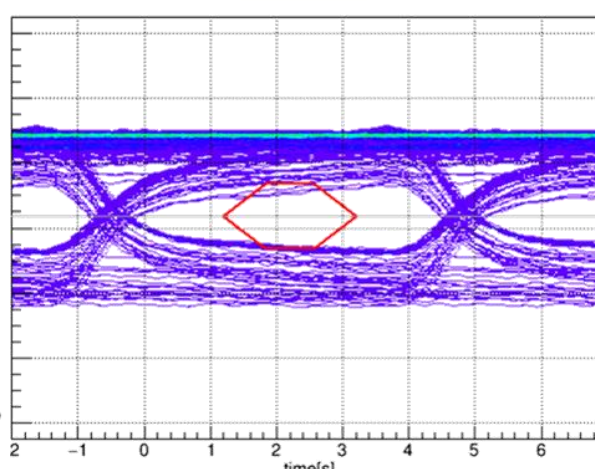
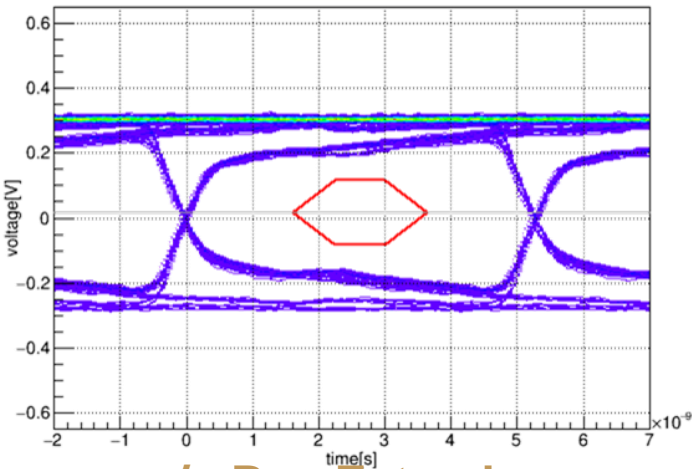
# Higher current drawing of LVDS

3mA

3mA

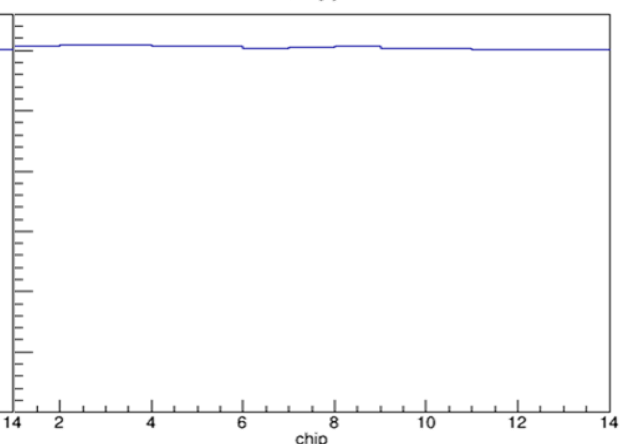
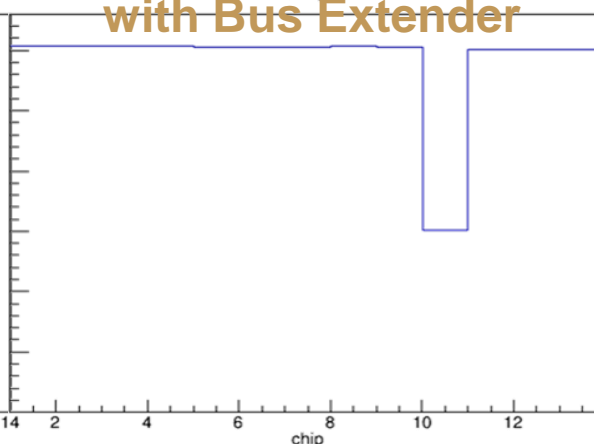
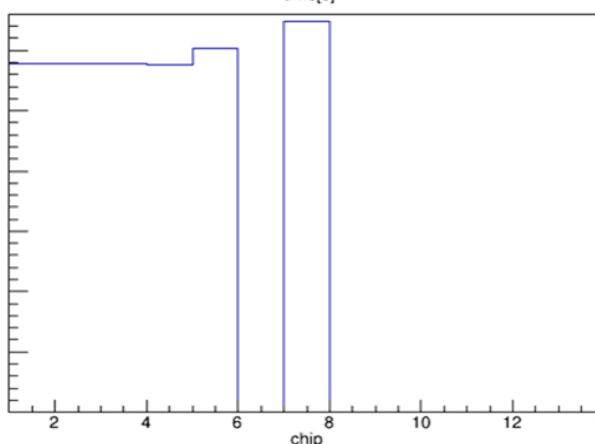
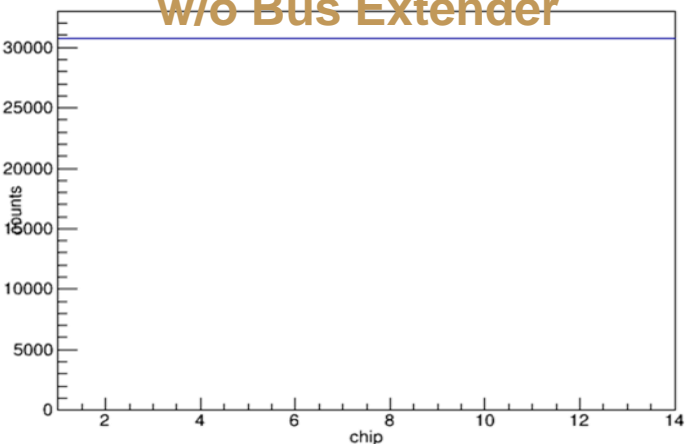
5mA

8mA



w/o Bus Extender

with Bus Extender



**We found that increasing the amount of current creates a margin in the waveform and reduces erroneous judgments.**



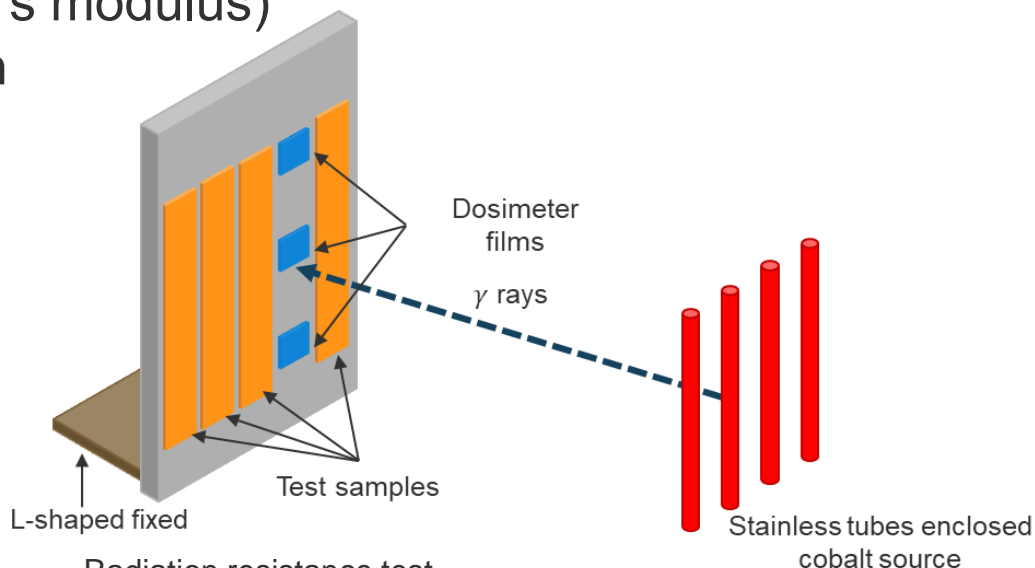


# Radiation hardness

- Long term stability under a radiation environment is important for INTT
  - Keep healthy for at least three years of operation
  - Bus Extender is produced with advanced materials, LCP and adhesive sheet.  
Good to know the radiation hardness

- FPC samples are exposed by strong Gamma source(<sup>60</sup>Co)@QST Japan
  - Radiation dose: 5 kGy, 500 kGy, 1000 kGy

- Evaluate radiation hardness with two mechanical quantities
  - Stiffness (Young's modulus)
  - Peeling Strength



Radiation resistance test

@Takasaki Advanced Radiation Research Institute

Preparation room



Dosimeter films  
 Range : 1 – 150kGy  
 Accuracy : 7% 5 – 150kGy



# Evaluation methods

- Young's modulus
  - Vibrate the sample and measure the natural freq. by the LASER system

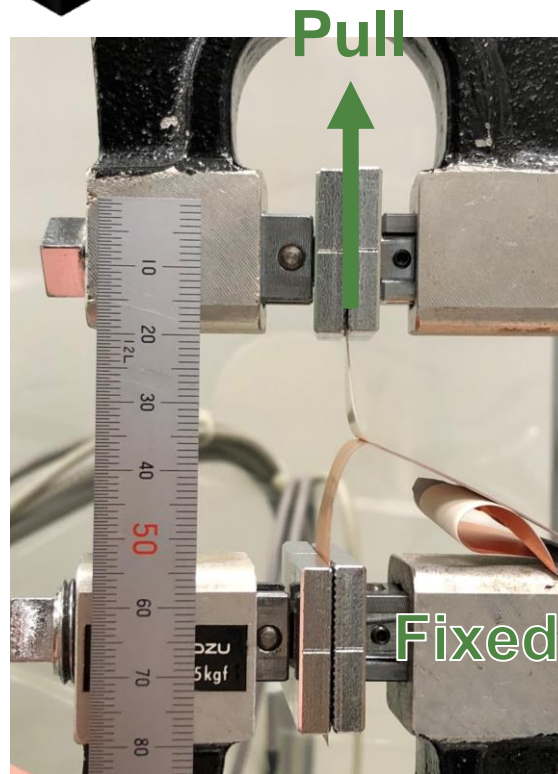
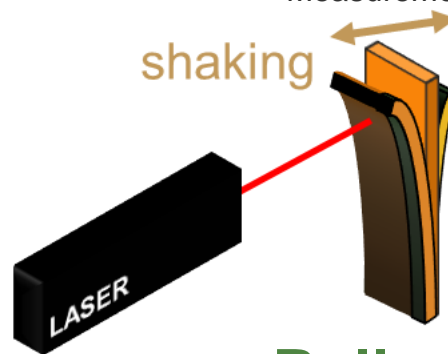
The relational expression between natural frequency and Young's modulus

$$f_n = a\sqrt{bE}$$

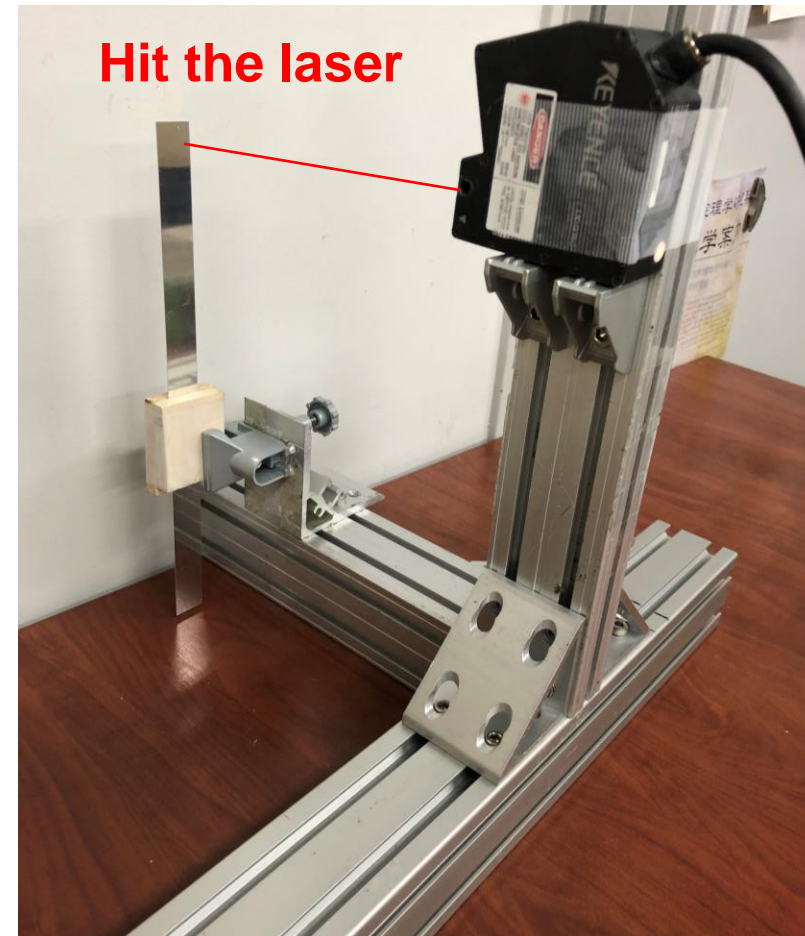
$f_n$  : Natural frequency  
 $E$  : Young's modulus  
 $a$  : Coefficient 1  
 $b$  : Coefficient 2

- Peel strength
  - Sample peeled off at 180 degrees and measure its strength by a tensile tester

Measurement of natural frequency @Rikkyo Univ.

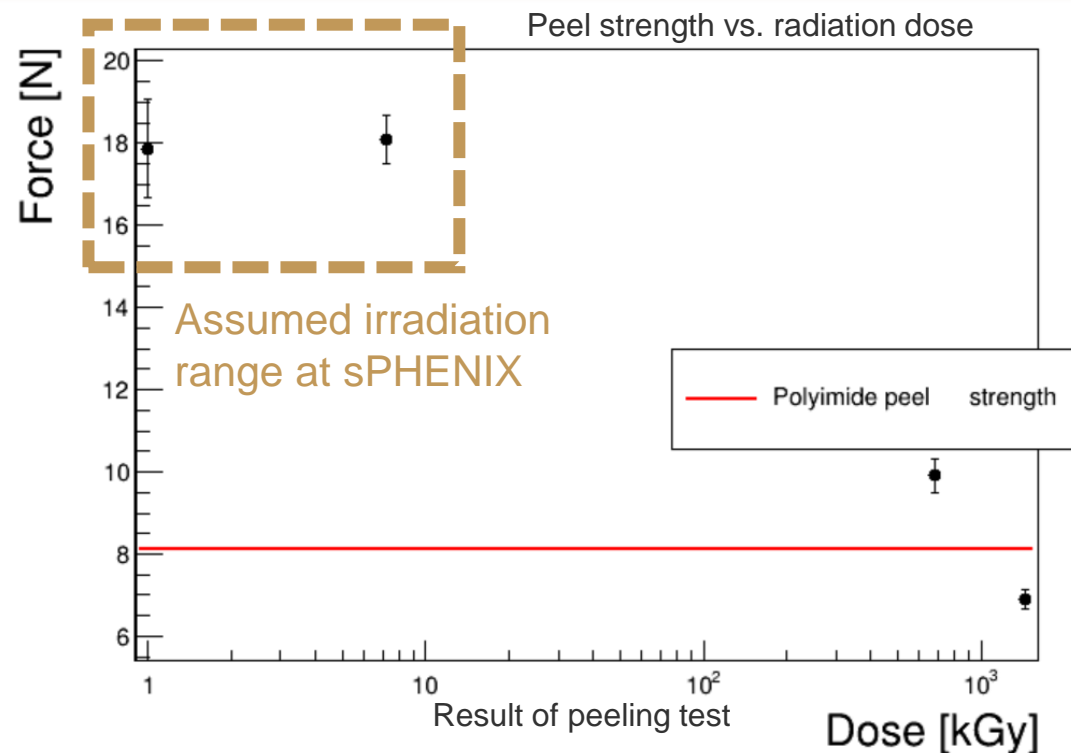
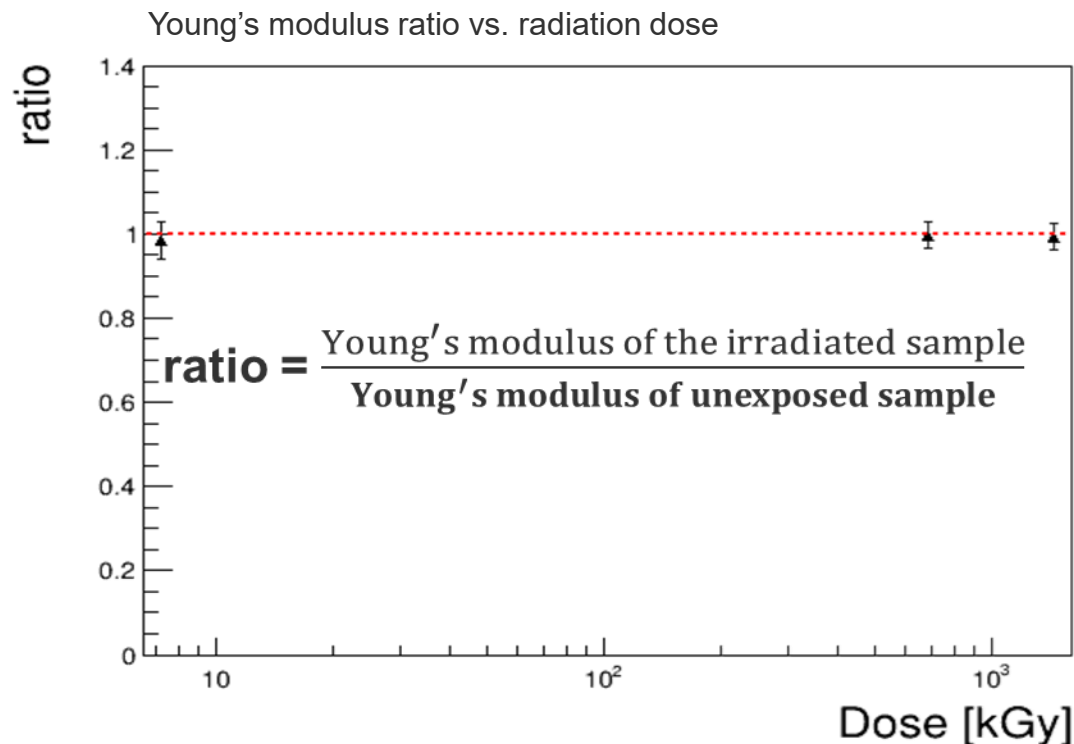


Peeling test using a tensile tester  
INTT Bus Extender Performance





# Results of mechanical quantities



- Young's modulus : No change within 7% uncertainties by radiation exposure
- Peel strength : No change for sPHENIX data taking and get smaller clearly for the higher exposure

**Radiation hardness of Bus Extender is good enough for sPHENIX**

## Electrical properties and Radiation hardness were studied

### Electrical Properties

- Calibration test is useful with Bus Extender
  - The threshold becomes high because of the attenuation of the test pulse.
- The pulse shape of the signal transmission is distorted.
- Increasing the amount of current creates a margin in the waveform and reduces erroneous judgments.

### Radiation hardness

- Evaluate using Young's modulus and peel strength
- No change of Young's modulus within the error of 7%
- No change of the peel strength for irradiation range at sPHENIX

**Bus Extender is ready for mass production**  
**Mass production of the Bus Extender will start in 2021**

# Back Up

